

Identity card

Name: **PosiTectorRTR-P_Machined_surface**

Axis: **X**

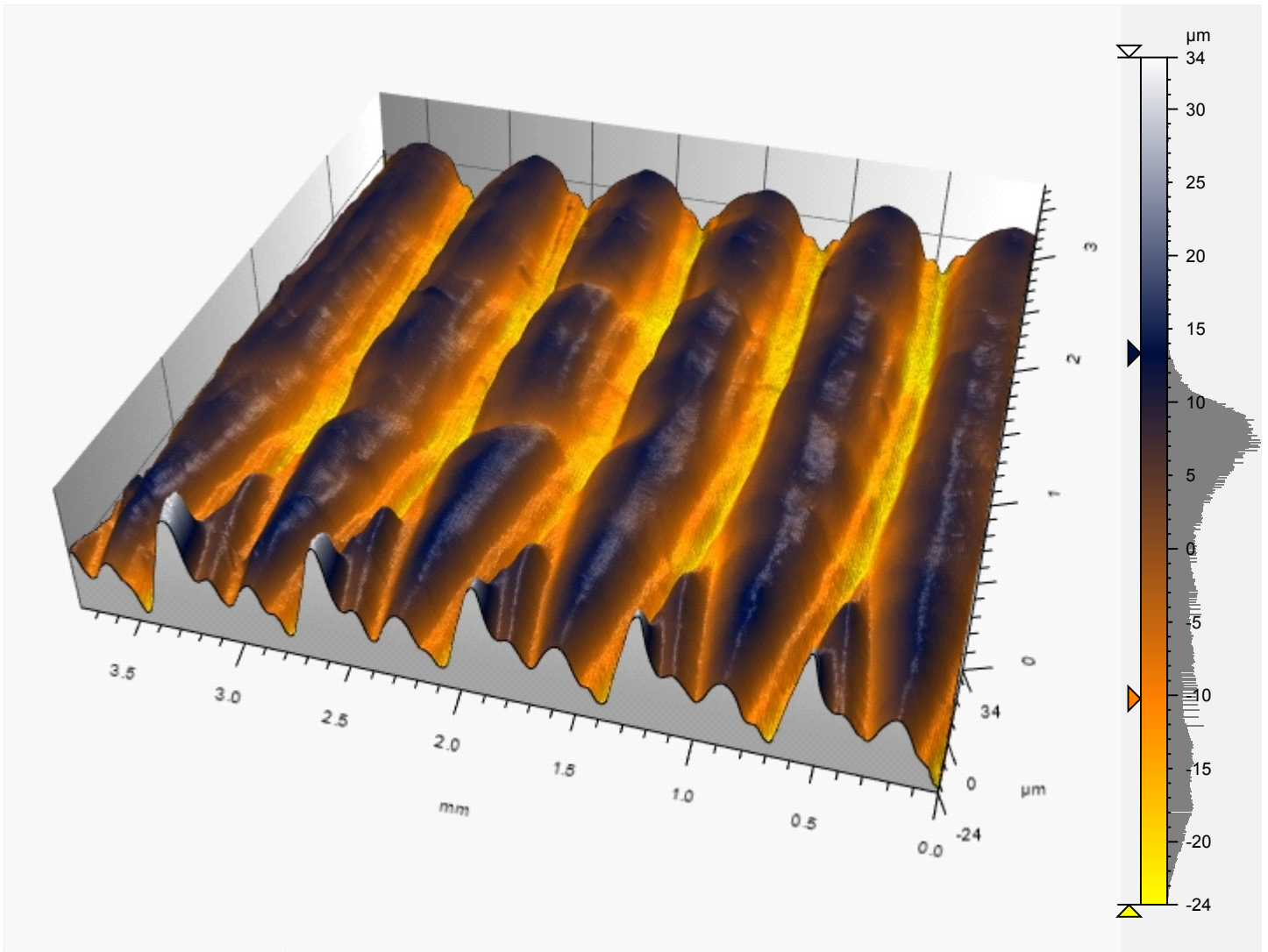
Length: **3.8 mm**

Axis: **Y**

Length: **3.8 mm**

Axis: **Z**

Length: **58 μm**



ISO 25178

Height Parameters

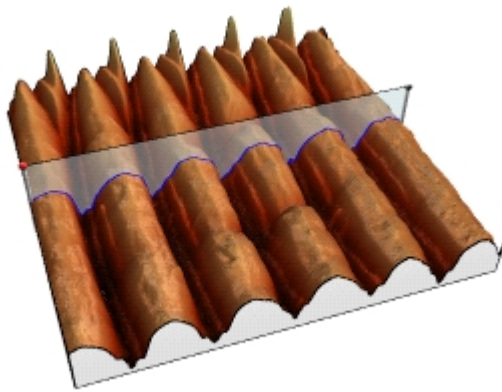
Sa	7.8	μm		Arithmetic mean height
Sq	9.1	μm		Root-mean-square height
Ssk	-0.63			Skewness
Sku	2.4			Kurtosis
Sz	58	μm		Maximum height

Functional Parameters

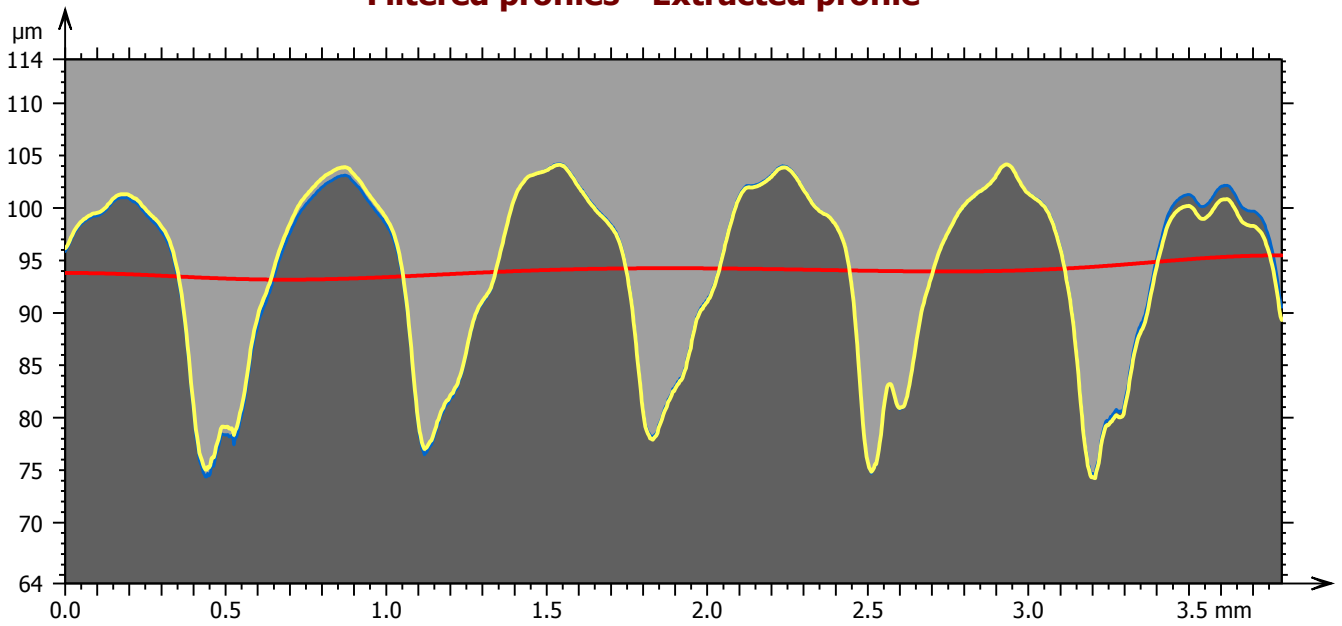
Smr	0.18	%	$c = 10 \mu\text{m}$ under the highest peak	Areal material ratio
Smc	9.3	μm	$p = 10\%$	Inverse areal material ratio
Sxp	22	μm	$p = 50\%, q = 98\%$	Extreme peak height

For demonstration purposes only!

Summary of last operator



Filtered profiles - Extracted profile



Information	
Profile	Roughness profile & Waviness profile
Filter settings	<i>Gaussian filter, cut-off 2.5 mm, End effects managed</i>

ISO 4287				
Amplitude parameters - Roughness profile				
Ra	7.5	µm	<i>Gaussian filter, 2.5 mm, End effects managed</i>	<i>Arithmetic Mean Deviation of the roughness profile.</i>
Rq	8.6	µm	<i>Gaussian filter, 2.5 mm, End effects managed</i>	<i>Root-Mean-Square (RMS) Deviation of the roughness profile.</i>
Rz	29	µm	<i>Gaussian filter, 2.5 mm, End effects managed</i>	<i>Maximum Height of roughness profile.</i>
Rt	30	µm	<i>Gaussian filter, 2.5 mm, End effects managed</i>	<i>Total Height of roughness profile.</i>
Spacing parameters - Primary profile				
PSm	0.68	mm		<i>Mean Width of the raw profile elements.</i>
Pdq	6.5	°		<i>Root-Mean-Square Slope of the raw profile.</i>
ASME B46.1				
2D Parameters				
Wt	12	µm	<i>Gaussian filter, 0.8 mm</i>	<i>Total Height of waviness profile.</i>

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